

**Search Notes****Application/Control No.**

10/750,599

**Examiner**

Hai L. Nguyen

**Applicant(s)/Patent under Reexamination**

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**Art Unit**

2816

**SEARCHED**

Class	Subclass	Date	Examiner
327	551-559	6/18/2005	HLN
327	175,311		
327	531,532		
333	172		
340	825.71		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with DinhLE, Primary Examiner, AU # 2816	6/16/2005	HLN
EAST Text Search	6/18/2005	HLN
Shepardize Search	6/20/2005	HLN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner